

10583660_CLSTI TLES
Titles of most frequently occurring classifications of patents returned
from a search of 10583660 on Apr 20 , 2009

4 430/ 5 (4 OR, 0 XR)
Class 430 RADI ATI ON I MAGERY CHEM STRY: PROCESS, COMPOSI TI ON, OR
PRODUCT THEREOF
430/ 4 . RADI ATI ON MODI FYING PRODUCT OR PROCESS OF MAKING
430/ 5 .. Radi at i on mask

4 250/ 492. 2 (1 OR, 3 XR)
Class 250 RADI ANT ENERGY
250/ 492. 1 . I RRADI ATI ON OF OBJECTS OR MATERI AL
250/ 492. 2 .. Irradi at i on of semi conductor devi ces

4 382/ 141 (3 OR, 1 XR)
Class 382 I MAG E ANALYSI S
382/ 100 . APPLI CATI ONS
382/ 141 .. Manuf acturing or product i nspect i on

3 250/ 491. 1 (2 OR, 1 XR)
Class 250 RADI ANT ENERGY
250/ 491. 1 . MEANS TO ALIGN OR POSI TI ON AN OBJECT RELATI VE TO A SOURCE
OR DETECTOR

3 356/ 71 (2 OR, 1 XR)
Class 356 OPTI CS: MEASURI NG AND TESTI NG
356/ 71 . DOCUMENT PATTERN ANALYSI S OR VERIFI CATI ON

2 382/ 147 (1 OR, 1 XR)
Class 382 I MAG E ANALYSI S
382/ 100 . APPLI CATI ONS
382/ 141 .. Manuf acturing or product i nspect i on
382/ 145 ... Inspection of semi conductor device or printed circuit
board
382/ 147 Inspecting printed circuit boards

2 382/ 149 (1 OR, 1 XR)
Class 382 I MAG E ANALYSI S
382/ 100 . APPLI CATI ONS
382/ 141 .. Manuf acturing or product i nspect i on
382/ 145 ... Inspection of semi conductor device or printed circuit
board
382/ 149 Fault or defect detect i on

2 348/ 126 (0 OR, 2 XR)
Class 348 TELEV SI ON
348/ 61 . SPECI AL APPLI CATI ONS
348/ 125 .. Fl aw detect or
348/ 126 ... Of electronic circuit chip or board

2 250/ 310 (1 OR, 1 XR)
Class 250 RADI ANT ENERGY
250/ 306 . I NSPECTI ON OF SOLI DS OR LI QUI DS BY CHARGED PARTI CLES
250/ 310 .. El ectron probe type

2 250/ 307 (1 OR, 1 XR)
Class 250 RADI ANT ENERGY
250/ 306 . I NSPECTI ON OF SOLI DS OR LI QUI DS BY CHARGED PARTI CLES
250/ 307 .. Met hods

2 430/ 322 (0 OR, 2 XR)
Class 430 RADI ATI ON I MAGERY CHEM STRY: PROCESS, COMPOSI TI ON, OR

10583660_CLSTI TLES

PRODUCT THEREOF

	430/ 269	. IMAGING AFFECTING PHYSICAL PROPERTY OF RADIATION SENSITIVE MATERIAL, OR PRODUCING NONPLANAR OR PRINTING SURFACE - PROCESS, COMPOSITION, OR PRODUCT
	430/ 322	. . Forming nonplanar surface
2	714/ 720	(2 OR, 0 XR)
	Class 714	ERROR DETECTION/ CORRECTION AND FAULT DETECTION/ RECOVERY
	714/ 699	. PULSE OR DATA ERROR HANDLING
	714/ 718	. . Memory testing
	714/ 719	. . . Read-in with read-out and compare
	714/ 720	. . . Special test pattern (e.g., checkerboard, walking ones)
2	365/ 200	(0 OR, 2 XR)
	Class 365	STATIC INFORMATION STORAGE AND RETRIEVAL
	365/ 189. 011	. READ/ WRITE CIRCUIT
	365/ 200	. . Bad bit
2	714/ 766	(0 OR, 2 XR)
	Class 714	ERROR DETECTION/ CORRECTION AND FAULT DETECTION/ RECOVERY
	714/ 699	. PULSE OR DATA ERROR HANDLING
	714/ 746	. . Digital data error correction
	714/ 752	. . . Forward correction by block code
	714/ 763	. . . Memory access
	714/ 766	. . . Check bits stored in separate area of memory
2	714/ E11. 036	(0 OR, 2 XR)
	Class 714	ERROR DETECTION/ CORRECTION AND FAULT DETECTION/ RECOVERY
	714/ E11. 001	. . ERROR DETECTION; ERROR CORRECTION; MONITORING (EPO)
	714/ E11. 021	. . Responding to the occurrence of a fault, e.g., fault tolerance, etc. (EPO)
	714/ E11. 03	. . . Error detection or correction by redundancy in data representation, e.g., by using checking codes, etc. (EPO)
	714/ E11. 032	. . . Adding special bits or symbols to the coded information, e.g., parity check, casting out 9's or 11's, etc. (EPO)
	714/ E11. 034	. . . In memories (EPO)
	714/ E11. 035	. . . In static stores (EPO)
	714/ E11. 036	. . . Integrated on a chip (EPO)
2	714/ 805	(0 OR, 2 XR)
	Class 714	ERROR DETECTION/ CORRECTION AND FAULT DETECTION/ RECOVERY
	714/ 699	. PULSE OR DATA ERROR HANDLING
	714/ 799	. . Error/ fault detection technique
	714/ 800	. . . Parity bit
	714/ 805	. . . Storage accessing (e.g., address parity check)
2	365/ 201	(0 OR, 2 XR)
	Class 365	STATIC INFORMATION STORAGE AND RETRIEVAL
	365/ 189. 011	. READ/ WRITE CIRCUIT
	365/ 201	. . Testing